Security, Cybercrime, and Digital Forensics for the IoT

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Message from the Guest Editor

This Special Issue invites contributions and recent advancements in investigating and addressing security and privacy challenges for smart sensors, emphasizing cybercrimes and digital forensics. Topics in this Special Issue can include (but are not limited to):

- Cybercrime and digital forensics for the IoT
- Incident response methods for the IoT
- Data analysis of the IoT for forensic investigation
- System, network, and mobile forensics for the IoT
- AI-accelerated intrusion detection for the IoT
- Reverse-engineering and forensic activities for the IoT
- Cybercrime risk management for the IoT
- Cryptography protocols and algorithms for the IoT
- Blockchain and digital identity management in the IoT
- Intrusion and malware detection for the IoT
- Security, privacy, and trust in the IoT
- Other challenges and soultions for IoT security and forensics

Special Issue

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Message from the Editor-in-Chief

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